



STLVD112

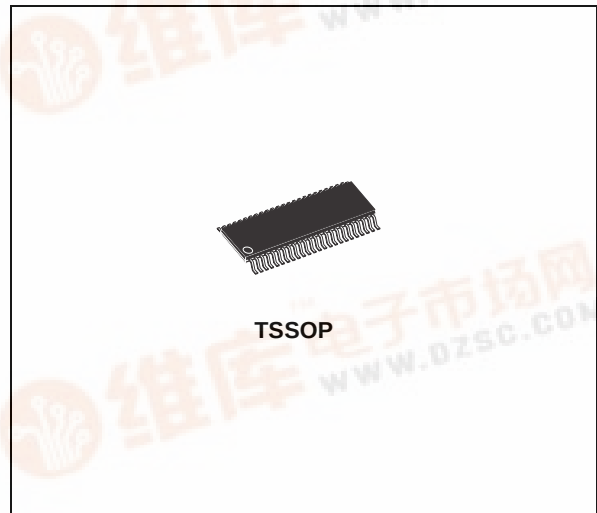
HIGH SPEED PROTECTION SWITCH

- 24mA CMOS OUTPUT DRIVE CURRENT
- LVTTTL INPUT THRESHOLDS
- CONTROLLED SKEW BETWEEN DATA AND CLOCK SIGNALS
- LVDS INPUT-OUTPUT UP TO 155 MHZ
- IMPROVED LATCH-UP IMMUNITY UP TO 300mA

DESCRIPTION

The STLVD112 is a low voltage differential to LVTTTL signal converter with enhanced loop-back and crosspoint features. The synchronous design allows a phase alignment between a clock and its data; this means a better BER (Bit Error Rate) performance.

The advanced 0.35μm technology makes the STLVD112 suitable for data rates up to 200Mbit. The main application field is SDH/SONET telecom infrastructure. The STLVD112 flexible switch architecture makes it easy to implement multiple protection schemes in STM1 access systems. Thanks to the flexible multiplexing allowed, it becomes simple to redirect the data/clock signal coming from the faulty access card to the spare card. In normal mode the STLVD112 converts the differential data levels of the LVDS and related

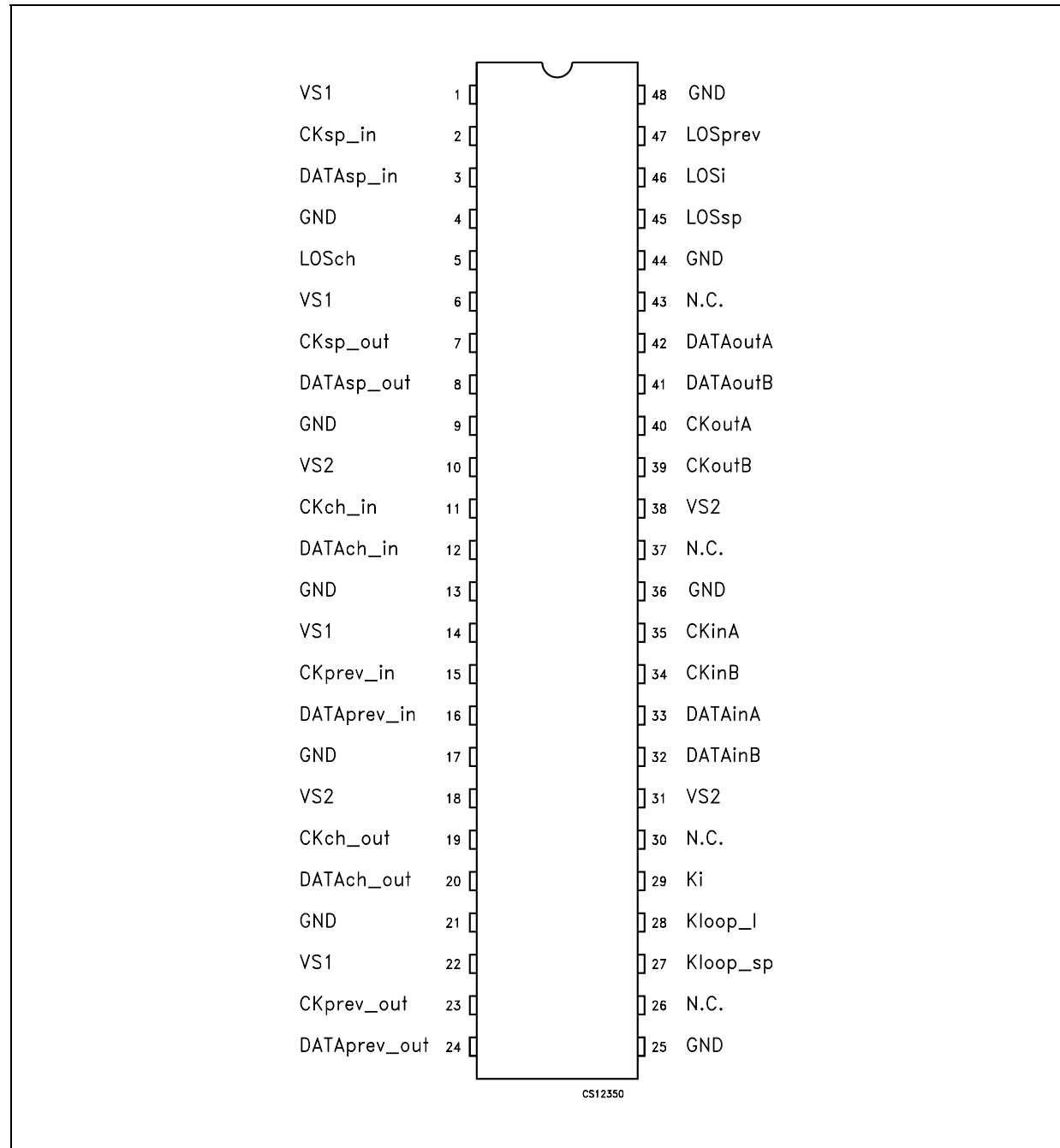


clock signal from (to) the line interface in LVTTTL level signals to (from) the backpanel. In addition the switch functions prevent the equipment from line interface faults. In fact, it is possible to switch the signals coming from a different line interface to the local line interface or the signals from the local line interface to a different line interface.

ORDERING CODES

Type	Temperature Range	Package	Comments
STLVD112BTR	-40 to 85 °C	TSSOP48 (Tape & Reel)	1000 parts per reel
STLVD112CTR	0 to 70 °C	TSSOP48 (Tape & Reel)	1000 parts per reel

PIN CONFIGURATION



PIN DESCRIPTION

PIN N°	SYMBOL	NAME AND FUNCTION
1, 6, 14, 22	VS1	Main Power Supply
2	CKsp_in	LVTTL Clock Input
3	DATAsp_in	LVTTL Data Input
4, 9, 13, 17, 21, 25, 36, 44, 48	GND	Ground
5	LOSch	Control Output
7	CKsp_out	LVTTL Clock Output
8	DATAsp_out	LVTTL Data Output
10, 18, 31, 38	VS2	Second Power Supply
11	CKch_in	LVTTL Clock Input
12	DATAch_in	LVTTL Data Input
15	CKprev_in	LVTTL Clock Input
16	DATApv_in	LVTTL Data Input
19	CKch_out	LVTTL Clock Output
20	DATAch_out	LVTTL Data Output
23	CKprev_out	LVTTL Clock Output
24	DATApv_out	LVTTL Data Output
26, 30, 37, 43	N.C.	Not Connected
27	Kloop_sp	Control Input
28	Kloop_i	Control Input
29	Ki	Control Input
32	DATAinB	LVDS Data Input -
33	DATAinA	LVDS Data Input +
34	CKinB	LVDS Clock Input -
35	CKinA	LVDS Clock Input +
39	CKoutB	LVDS Clock Output -
40	CKoutA	LVDS Clock Output +
41	DATAoutB	LVDS Data Output -
42	DATAoutA	LVDS Data Output +
45	LOSp	Control Output
46	LOSi	Control Input
47	LOSprev	Control Input

TRUTH TABLES FOR THE FIVE MUX

INPUTS			OUTPUT
Ki	Kloop_sp	Kloop_i	DATA_out
LOW	X	X	DATAch_in
HIGH	X	X	DATAsp_in

INPUTS			OUTPUT
Ki	Kloop_sp	Kloop_i	DATAch_out
X	X	LOW	DATAin
X	X	HIGH	DATAch-in

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INPUTS			OUTPUT
Ki	Kloop_sp	Kloop_i	DATAsp_out
LOW	LOW	X	DATAprev_in
HIGH	LOW	X	DATA_in
X	HIGH	X	DATAsp_in

INPUTS			OUTPUT
Ki	Kloop_sp	Kloop_i	LOSch
X	X	LOW	LOSi
X	X	HIGH	LOW

INPUTS			OUTPUT
Ki	Kloop_sp	Kloop_i	LOSp
LOW	LOW	X	LOSprev
HIGH	LOW	X	LOSi
X	HIGH	X	LOW

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
VS1, VS2	Supply Voltage	-0.3 to 4.6	V
VS2	Supply Voltage	-0.3 to (VS1 + 0.3)	V
V _I	DC Input Voltage	-0.3 to (VS1 + 0.3)	V
V _O	DC Output Voltage	-0.3 to (VS1 + 0.3)	V
I _{ik}	DC Input Diode Clamp Current	±20	mA
I _{ok}	DC Output Diode Clamp Current	±20	mA
I _O	DC Output Current	±50	mA
T _L	Lead Temperature (10sec)	300	°C
T _{stg}	Storage Temperature Range	-65 to 150	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
VS1, VS2	Supply Voltage	3 to 3.6	V
VS2	Supply Voltage	3 to (VS1 + 0.3)	V
V _I	DC Input Voltage	0 to VS1	V
V _O	DC Output Voltage	0 to VS1	V
Top	Operating Temperature	-45 to 85	°C
dt/dv	Maximum Input Rise and Fall Time	10	ns/V

ELECTRICAL CHARACTERISTICS (Over recommended operating conditions, unless otherwise noted. All typical values are at $T_A=25^\circ\text{C}$ and $V_{S1}, V_{S2} = 3.3\text{V}$)

Symbol	Parameter	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
V_{OL}	Low Level Output Voltage	$I_{OUT} = 24\text{ mA}$		0.2	0.4	V
V_{OH}	High Level Output Voltage	$I_{OUT} = 24\text{ mA}$	$V_{SI}-0.5$	$V_{SI}-0.3$		V
V_{IL}	Low Level Input Thresholds	$V_{OUT} = 0.1\text{V}$ or $V_{S1} - 0.1$	0		0.8	V
V_{IH}	High Level Input Thresholds	$V_{OUT} = 0.1\text{V}$ or $V_{S1} - 0.1$	2		V_{SI}	V
I_{IN}	Input Leakage Current	$V_{IN} = \text{GND}$ or V_{CC}	-1		1	μA
I_{CC}	Quiescent Supply Current	$V_{IN} = \text{GND}$ or V_{CC}		15		mA
		$f_{CLOCK} = 155\text{MHz}$		110		

LVDS DRIVER ELECTRICAL CHARACTERISTICS (Over recommended operating conditions, unless otherwise noted. All typical values are at $T_A=25^\circ\text{C}$ and $V_{S1}, V_{S2} = 3.3\text{V}$)

Symbol	Parameter	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
V_{OD}	Differential Output Voltage	$R_L = 100\ \Omega$	247	364	454	mV
ΔV_{OD}	Change in differential output voltage between logic states		-50		50	mV
$V_{OC(SS)}$	Steady-state common-mode output voltage		1	1.15	1.30	V
$\Delta V_{OC(SS)}$	Change in steady-state common-mode output voltage between logic State		-50		50	mV
$\Delta V_{OC(PP)}$	Peak-to-Peak common-mode output voltage			100	150	mV
I_{SC}	Short Circuit Output Current	$V_{O(Y)} \text{ or } V_{O(Z)} = 0$	-24	-4		mA
		$V_{OD} = 0$			± 12	
I_{OFF}	Power Off Output Current	$V_{CC} = 0, V_O = 2.4\text{V}$	-1		1	μA

LVDS RECEIVER ELECTRICAL CHARACTERISTICS (Over recommended operating conditions, unless otherwise noted. All typical values are at $T_A=25^\circ\text{C}$ and $V_{S1}, V_{S2} = 3.3\text{V}$)

Symbol	Parameter	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
V_{ITH+}	Positive-going Differential Input Voltage Threshold				100	mV
V_{ITH-}	Negative-going Differential Input Voltage Threshold		-100			mV
$ V_{ID} $	Magnitude of Differential Input Voltage		0.1		0.6	V
V_{IC}	Common-mode Input Voltage		0.5		2.4-0.5	V
			$ V_{ID} $		$ V_{ID} $	
					$V_{CC}-1$	

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LVDS SWITCHING TIMING CHARACTERISTICS (Over recommended operating conditions, unless otherwise noted. All typical values are at $T_A=25^\circ\text{C}$ and $V_{S1}, V_{S2} = 3.3\text{V}$)

Symbol	Parameter	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
t_W	Minimum Pulse Width		<1			ns

AC LVTTTL IN LVTTTL OUT (Over recommended operating conditions, unless otherwise noted. All typical values are at $T_A=25^\circ\text{C}$ and $V_{S1}, V_{S2} = 3.3\text{V}$)

Symbol	Parameter	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
t_{PLH}	Propagation Delay Time, low-to-high-level output (50% to 50%)	Measured with $V_{IN}=0$ to 2.5V , $f_{CLOCK} = 1\text{MHz}$, $f_{DATA} = 0.5\text{MHz}$ $t_r = t_f = 0.4\text{ns}$, +Duty Cycle=50% t_{PHL} , t_{PLH} are referred to output clock transitions.	2.4	3.9	5.6	ns
t_{PHL}	Propagation Delay Time, high-to-low-level output (50% to 50%)		2.5	4.2	5.3	ns
t_{TLH}	Transition Time, low-to-high-level output (10% to 90%)		0.7	1.3	1.6	ns
t_{THL}	Transition Time, high-to-low-level output (90% to 10%)		0.7	1.1	1.3	ns
f_{opr}	Operative frequency		100	155	200	MHz

AC CONTROL OUTPUT (LOSsp, LOSch) (Over recommended operating conditions, unless otherwise noted. All typical values are at $T_A=25^\circ\text{C}$ and $V_{S1}, V_{S2} = 3.3\text{V}$)

Symbol	Parameter	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
t_{PLH}	Propagation Delay Time, low-to-high-level output (50% to 50%)	Measured with $V_{IN}=0$ to 2.5V , $f_{CLOCK} = 1\text{MHz}$, $f_{DATA} = 0.5\text{MHz}$ $t_r = t_f = 0.4\text{ns}$, +Duty Cycle=50% t_{PHL} , t_{PLH} are referred to output clock transitions.	2.4	3.6	4.4	ns
t_{PHL}	Propagation Delay Time, high-to-low-level output (50% to 50%)		2.4	3.4	4.2	ns
t_{TLH}	Transition Time, low-to-high-level output (10% to 90%)		0.9	1.9	2.3	ns
t_{THL}	Transition Time, high-to-low-level output (90% to 10%)		0.7	1.0	1.2	ns

AC LVTTTL IN LVDS OUT (Over recommended operating conditions, unless otherwise noted. All typical values are at $T_A=25^\circ\text{C}$ and $V_{S1}, V_{S2} = 3.3\text{V}$)

Symbol	Parameter	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
t_{PLH}	Propagation Delay Time, low-to-high-level output (50% to 50%)	Measured with $V_{IN}=0$ to 2.5V , $f_{CLOCK} = 1\text{MHz}$, $f_{DATA} = 0.5\text{MHz}$ $t_r = t_f = 0.4\text{ns}$, +Duty Cycle=50% t_{PHL} , t_{PLH} are referred to output clock transitions.	2.8	3.8	4.7	ns
t_{PHL}	Propagation Delay Time, high-to-low-level output (50% to 50%)		2.6	3.4	4.1	ns
t_{TLH}	Transition Time, low-to-high-level output (20% to 80%)		0.4	0.5	0.6	ns
t_{THL}	Transition Time, high-to-low-level output (80% to 20%)		0.4	0.6	0.7	ns
f_{opr}	Operative frequency		100	155	200	MHz

AC LVDS IN LVTTTL OUT (Over recommended operating conditions, unless otherwise noted. All typical values are at $T_A=25^\circ\text{C}$ and $V_{S1}, V_{S2} = 3.3\text{V}$)

Symbol	Parameter	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
t_{PLH}	Propagation Delay Time, low-to-high-level output (50% to 50%)	$V_{DIFF} = 400\text{mV}$ Measured with $V_{ICM} = 1.2\text{ V}$, $f_{CLOCK} = 1\text{MHz}$, $f_{DATA} = 0.5\text{MHz}$ $t_r = t_f = 0.4\text{ns}$, +Duty Cycle=50% t_{PHL}, t_{PLH} are referred to output clock transitions	4.3	5.6	6.9	ns
t_{PHL}	Propagation Delay Time, high-to-low-level output (50% to 50%)		4.1	5.4	6.7	ns
t_{TLH}	Transition Time, low-to-high-level output (10% to 90%)		0.7	0.9	1.1	ns
t_{THL}	Transition Time, high-to-low-level output (90% to 10%)		0.8	1.0	1.3	ns
f_{opr}	Operative frequency		100	155	200	MHz

LVTTTL IN LVTTTL OUT ($V_{CC} = 3$ to 3.6V $T_A = -45$ to 80°C , unless otherwise noted. Typical values are at $T_A = 25^\circ\text{C}$)

Symbol	Parameter	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
t_s	Setup Time	$f = 10\text{MHz}$, $V_{ICM} = 1.2\text{ V}$	1			ns
t_{H-}	Hold Time	$V_{DIFF} = 400\text{mV}$, $V_{INTTL} = 0$ to 2.5V	1			ns

LVTTTL IN LVDS OUT (Over recommended operating conditions, unless otherwise noted. All typical values are at $T_A=25^\circ\text{C}$ and $V_{S1}, V_{S2} = 3.3\text{V}$)

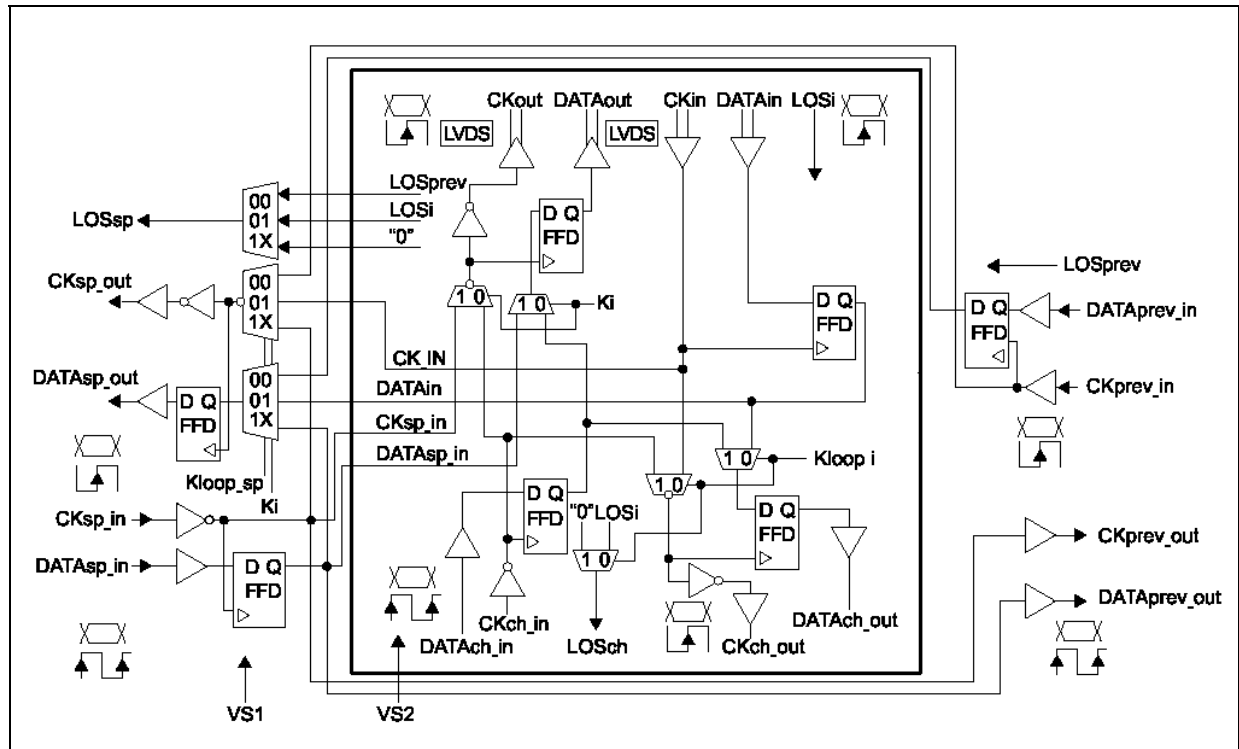
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			Min.	Typ.	Max.	
t_s	Setup Time	$f = 10\text{MHz}$, $V_{ICM} = 1.2\text{ V}$	1			ns
t_{H-}	Hold Time	$V_{DIFF} = 400\text{mV}$, $V_{INTTL} = 0$ to 2.5V	1			ns

LVDS IN LVTTTL OUT (Over recommended operating conditions, unless otherwise noted. All typical values are at $T_A=25^\circ\text{C}$ and $V_{S1}, V_{S2} = 3.3\text{V}$)

Symbol	Parameter	Test Conditions	Value			Unit
			Min.	Typ.	Max.	
t_s	Setup Time	$f = 10\text{MHz}$, $V_{ICM} = 1.2\text{ V}$	1.5			ns
t_{H-}	Hold Time	$V_{DIFF} = 400\text{mV}$, $V_{INTTL} = 0$ to 2.5V	1			ns

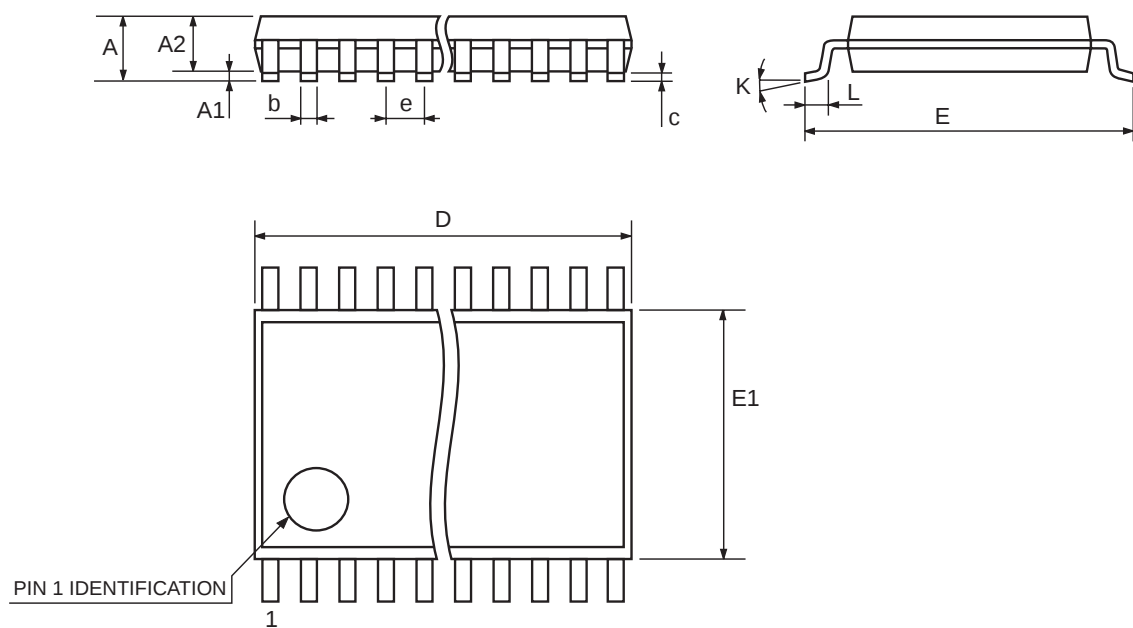
STLVLD112

LOGIC DIAGRAM



TSSOP48 MECHANICAL DATA

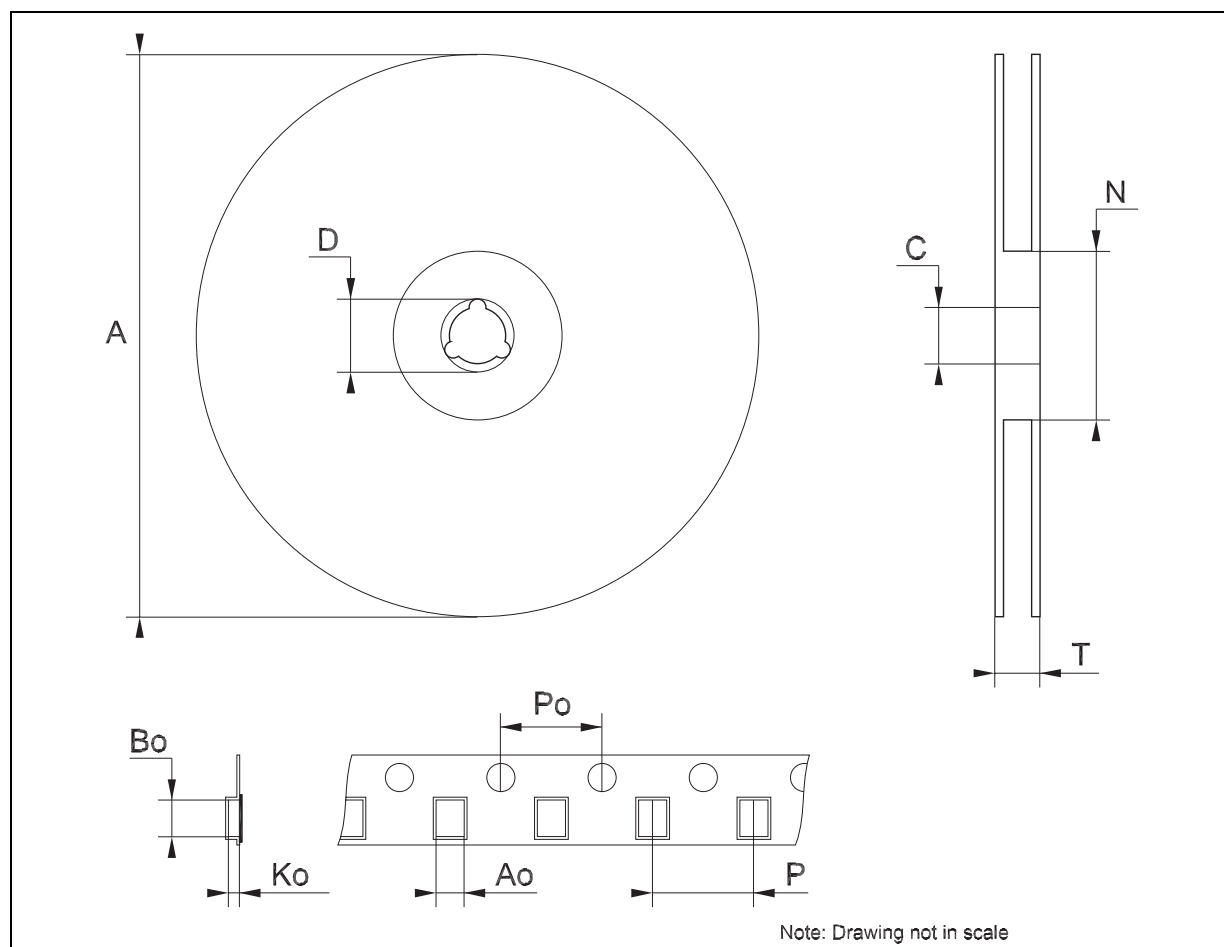
DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A			1.2			0.047
A1	0.05		0.15	0.002		0.006
A2		0.9			0.035	
b	0.17		0.27	0.0067		0.011
c	0.09		0.20	0.0035		0.0079
D	12.4		12.6	0.488		0.496
E		8.1 BSC			0.318 BSC	
E1	6.0		6.2	0.236		0.244
e		0.5 BSC			0.0197 BSC	
K	0°		8°	0°		8°
L	0.50		0.75	0.020		0.030



7065588C

Tape & Reel TSSOP48 MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A			330			12.992
C	12.8		13.2	0.504		0.519
D	20.2			0.795		
N	60			2.362		
T			30.4			1.197
Ao	8.7		8.9	0.343		0.350
Bo	13.1		13.3	0.516		0.524
Ko	1.5		1.7	0.059		0.067
Po	3.9		4.1	0.153		0.161
P	11.9		12.1	0.468		0.476



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